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CCS H83

SJ

# INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

# SJ 21444-2018

## Specification for gallium oxide monocrystalline wafers of beta -Ga203-N

β-Ga203-N 型氧化镓单晶片规范

**(English Translation)**

**Issued by: Ministry of Industry and Information Technology**

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## 1 Foreword

SJ 21444-2018 was issued by Ministry of Industry and Information Technology on 18 January 2018.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 11 pages in English translation.

## 2 Scope Preview

SJ 21444-2018 is filed under Chinese Standard Classification H83, in the field of metallurgy.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.



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## 3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 11 pages (approximate)

Chinese original: about 16,118 characters

## 4 Related standards

Standards on related subjects:

GB/T 25074-2017 - Solar-grade polycrystalline silicon

SJ/T 11488-2015 - Test method for measuring resistivity, hall coefficient and determining hall mobility in semi-insulating GaAs single crystals

YS/T 13-2015 - High pure germanium tetrachloride

SJ 21445-2018 - CdS-N type infrared/ultraviolet two-color detection cadmium sulfide single wafer specification

SJ 21443-2018 - GaN-N type low resistance gallium nitride single wafer specification

SJ 21442-2018 - GaN-based SI type semi-insulating gallium nitride single wafer specification

## 5 Classification and status

Chinese Standard Classification (CCS): H 83

Prefix SJ: mandatory standard.



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